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APPLICATION NO.	FILI	NG DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
10/601,048	10/601,048 06/20/2003		Dimitri Chernyak	018158-021800US	8453	
20350	7590 06/05/2006			EXAMINER		
TOWNSEND AND TOWNSEND AND CREW, LLP TWO EMBARCADERO CENTER EIGHTH FLOOR SAN FRANCISCO, CA 94111-3834				SANDERS	SANDERS JR, JOHN R	
				ART UNIT	- PAPER NUMBER	
				3735		

DATE MAILED: 06/05/2006

Please find below and/or attached an Office communication concerning this application or proceeding.

U.S. Patent and Trademark Office PTOL-326 (Rev. 7-05)

Paper No(s)/Mail Date

2) Notice of Draftsperson's Patent Drawing Review (PTO-948)

3) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08)

6) Other: \_

Notice of Informal Patent Application (PTO-152)

Art Unit: 3735

#### DETAILED ACTION

## **Drawings**

1. The drawings were received on 17 March 2006. These drawings are acceptable.

## Response to Arguments

2. Applicant's arguments with respect to claims 1-5, 6-15 and 17-37 have been considered but are most in view of the new ground(s) of rejection.

## Claim Rejections - 35 USC § 103

- 3. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
  - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 4. Claims 1-5, 7-10, 13-15, 17-26 and 29-37 are rejected under 35 U.S.C. 102(b) as anticipated by or, in the alternative, under 35 U.S.C. 103(a) as obvious over U.S. Patent Application Publication No. 2001/0041884 A1 to Frey et al ("Frey") in view of U.S. Patent No. 6,738,511 to Farrell et al ("Farrell").

Frey discloses a method for determining the wavefront aberrations of the eye, determining an optical correction for the eye based on said wavefront aberrations, and subsequently determining a laser ablation profile for ablating the eye to achieve said optical correction (abstract). Frey discloses aligning the eye with the probe beam path for wavefront measurement based upon the video image of the eye from a video imaging path (paragraph 31).

Frey discloses projecting light for reflection from the retina to be detected using a Hartmann-Shack wavefront sensor in order to measure across the pupil of the eye a set of local gradients corresponding to displaced spots produced by the lenslets in the Hartmann-Shack sensor (paragraphs 90-108). Frey discloses reconstructing the wavefront surface from the measured gradients with Zernike polynomials, but also discloses that other mathematical approaches can be used to approximate the distorted wavefront surface, including Fourier (paragraph 108).

Frey discloses determining a laser ablation treatment profile from the reconstructed wavefront, said laser treatment ablating a specified thickness from the cornea to effect the optical correction (paragraphs 199-219). Though Frey is primarily concerned with a reconstruction method based on Zernike polynomials, Frey expressly discloses the applicability of Fourier-based reconstruction. Thus, if Frey does not necessarily anticipate applying a Fourier transform to the measured gradients, one of ordinary skill in the art at least would find it obvious to do so based upon the suggestion by Frey of Fourier reconstruction as a viable alternative to Zernike polynomial reconstruction.

Frey discloses the above limitations but does not expressly disclose adjusting adding a mean gradient field to remove a tilt from the reconstructed surface. Farrell teaches a method for reconstructing a surface profile by converting a phase map to a gradient map. Farrell teaches the desirability of removing a tilt component from the phase difference measurements as a step in calculating the surface profile (col. 1, lines 49-54). Farrell further teaches that the tilt removed from the phase data is determined from calculating an average slope from slope data differentiated from the phase data (col. 3, lines 31-42).

At the time of the invention, it would have been obvious to one of ordinary skill in the art to modify Frey to adjust the gradients obtained by the means disclosed by Frey, i.e. a wavefront sensor, said adjustment made in view of a mean gradient field, as taught by Farrell, in order to remove a measured tilt from the reconstructed surface.

5. Claims 11 and 12 are rejected under 35 U.S.C. 103(a) as being unpatentable over Frey in view of Farrell, as applied to claim 1 above, and further in view of *Wavefront reconstruction* using iterative Fourier transforms, Applied Optics, 30:11 1325-1327 (1991) to Roddier et al ("Roddier"), of record.

Frey discloses applying Fourier-based reconstruction as previously discussed but does not expressly disclose applying a discrete Fourier decomposition and an inverse discrete Fourier transform. Roddier teaches wavefront construction using iterative Fourier transforms wherein an FFT algorithm is used to take the transform of arrays of sampled x and y slopes and then an inverse Fourier transform is applied (page 1325, column 2). At the time of the invention, it would have been obvious to one of ordinary skill in the art to modify Frey to apply the discrete Fourier transform and inverse Fourier transform as taught by Roddier in order to reconstruct the wavefront from the sampled wavefront slopes.

6. Claim 27 and 28 are rejected under 35 U.S.C. 103(a) as being unpatentable over Frey in view of Farrell, as applied to claim 20 above, and further in view of U.S. Patent No. 5,777,719 to Williams et al. ("Williams").

Art Unit: 3735

Frey discloses the above limitations but does not expressly disclose an adaptive optical element coupled to the processor. Williams teaches a device for measurement of wavefront aberrations of the eye with a Hartmann-Shack camera wherein a deformable mirror (118, fig. 1) is used in feedback with the processor to determine a wavefront profile for the eye. At the time of the invention, it would have been obvious to one of ordinary skill in the art to modify Frey to incorporate an adaptive optical element, as taught by Williams, in order to obtain stable wavefront measurements over time.

#### Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to John R. Sanders whose telephone number is (571) 272-4742. The examiner can normally be reached on M-F 10:00 am to 6:30 pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Charles Marmor, II can be reached on (571) 272-4730. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Application/Control Number: 10/601,048 Page 6

Art Unit: 3735

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25 May 2006

Charles A Marmor, IT SPE, A-1 Unit 3735